

**Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D  
Characterisation and Imaging with Ion Beams | (smr 2856)**

Contribution ID : 1

Type : **not specified**

## **Overview of the ICTP and IAEA relevant activities**

*Monday, 26 September 2016 09:30 (0:30)*

### **Content**

### **Summary**

**Presenter(s)** : SCANDOLO, Sandro (ICTP); SIMON, Aliz (IAEA)

**Session Classification** : DAY 1